

I Claim:

1. A circuit for detecting a focused ion beam attack, comprising:

a memory cell;

an antenna for detecting an FIB attack connected to said memory cell;

a driver circuit; and

a capacitance connected between said memory cell and said driver circuit, for isolating said driver circuit from said antenna.

2. The circuit according to claim 1, wherein said memory cell is a memory cell selected from the group consisting of a floating gate cell, an EEPROM cell, a flash cell, and a SONOS cell.

3. The circuit according to claim 1, wherein said memory cell comprises an electrically conductive electrode over a silicon area.

4. The circuit according to claim 1, wherein said memory cell is one of two memory cells connected to said antenna and isolated from said driver circuit by said capacitance.

5. The circuit according to claim 1, connected for operation as a FIB sensor of a smart card IC.